

# PATENT ABSTRACTS OF JAPAN

(11)Publication number : 04-231811

(43)Date of publication of application : 20.08.1992

(51)Int.Cl.

G01B 21/30

H01J 37/28

(21)Application number : 03-121080

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(22)Date of filing : 27.05.1991

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(30)Priority

Priority number : 02228009 Priority date : 31.08.1990 Priority country : JP

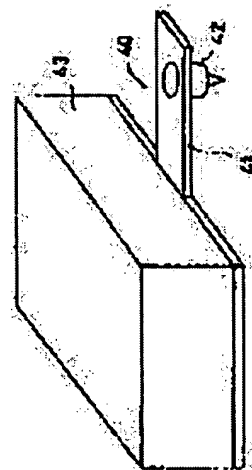
## (54) CANTILEVER FOR SCANNING TYPE PROBE MICROSCOPE AND MANUFACTURE THEREOF

(57)Abstract:

PURPOSE: To provide a cantilever provided with a probe part having a sharp tip and proper length.

CONSTITUTION: A cantilever 40 for a scanning type probe microscope is equipped with a lever part 40 and the probe part 42 arranged on the free end side thereof.

The probe part 42 consists of a conical tip part 45 having a sharp tip angle and the expanded base end part 44 continued to the tip part 45. The cantilever 40 is prepared by utilizing a semiconductor process.



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[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]

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